	Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-189001	Application No. 10/735,767	
	(Use several sheets if necessary)		Applicant Hideaki Kuwabara et al.		
			Filing Date December 16, 2003	Group Art Unit 2822	
ı	(37 CFR §1.98(b))				

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Information Disclosure Statement by Applicant (Use several sheets if necessary)

Hideaki Kuwabara et al.

Applicant

Filing Date

Group Art Unit 2822

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